

# Notic of References Cited

Application N  
10/003,121

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Examiner  
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Group Art Unit  
1752

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*	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
A	6,280,900 B1	8-28-01	Chiba et al.	430	270.1
B	6,281,318 B1	8-28-01	Yamamoto et al.	526	313
C	5,412,050	5-2-95	Watanabe et al.	526	313
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*	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS
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## NON-PATENT DOCUMENTS

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(See Manual of Patent Examining Procedure, Section 707.05(a).)